

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination AIKOH ET AL.	
			10/089,409 Examiner TAN X. DINH	Art Unit 2653	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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